

# Search Notes



Application/Control No.

10/010,779

Examiner

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Applicant(s)/Patent under Reexamination

EISENSTEIN, JONATHAN

Art Unit

3629

## SEARCHED

Class	Subclass	Date	Examiner
705	1	4/06	zon
	6		
	7		
	8		
	9		
	10		
	26		

## INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner

## SEARCH NOTES (INCLUDING SEARCH STRATEGY)

	DATE	EXMR
I US	4/06	zon
Patent		
PG Pub		
II FOREIGN		
1. EPO		
2. JPO		
3. Dement		
4. FRM-DOB		